

A GRAPHICAL USER INTERFACE FOR TESTING INTEGRATED CIRCUITS

ABSTRACT

5 A system that includes a graphical user interface (GUI)
connected to an input/output device of a computer system and
one or more test instruments producing a set of electrical
signals. The system also includes a probe card that has a
multiple probe needles used for measuring electronic
10 characteristics of each of the devices on a semiconductor
wafer. Each device has cells. Each cell has a set of bond
pads. The system also has a matrix switch and an interface
conduit electrically connecting the one or more test
instruments, the computer, the probe card, and the matrix
15 switch together. The semiconductor wafer is moved so that the
probe needles measure the electrical characteristics of each
cell for each device selected for testing.